


<p style="text-align: center;">Search Notes</p> 	<p>Application/Control No.</p> <p>10537127</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>JANEVSKI, ANGEL</p>
	<p>Examiner</p> <p>Takele, Meseker</p>	<p>Art Unit</p> <p>2174</p>

SEARCHED			
Class	Subclass	Date	Examiner
715	702, 716, 835	1/11/2008	MT
345	146, 173, 169	1/11/2008	MT

SEARCH NOTES		
Search Notes	Date	Examiner
East search (US-PGPUB, USPAT, USOCR, FPRS, EPO, JPO, DERWENT, IBM-TDB)	1/11/2008	MT
Discuss with Primary Sy Luu	1/11/2008	MT
Discuss with Xiao Wu	1/11/2008	MT
Inventor search	1/11/2008	MT

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner